

[232] Attorney Docket No. : ADP-131.1US

PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Lisa C. Chacon, Adam J. G. Ellison, George B. Hares,  
 Jeffrey T. Kohli, Josef C. Lapp, and Robert Morena  
 Serial No. : 09/990,750  
 Filed : November 16, 2001  
 For : GLASSES FOR FLAT PANEL DISPLAYS  
 Examiner : K. Group  
 Group : 1755

Commissioner of Patents and Trademarks  
 Washington, D.C. 20231

SUPPLEMENTAL LISTING UNDER 37 CFR §1.98(a)(1)U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>	<u>Classification Class</u>	<u>Sub</u>
<u>m</u>	33. 2,231,811	2/1941	Littleton et al.	49	89
<u>m</u>	34. 5,244,847	9/1993	Kushitani et al.	501	66
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<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>CLASS</u>
<u>n</u>	36. 8-034634	2/1996	JP	+
	with attached English abstract and computer translation obtained from the Japanese Patent Office website			
<u>n</u>	37. 9-156953	6/1997	JP	+
	with attached English translation			

Examiner  
 Signature: Kelly

Date

Considered: 8/19/03

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with attached English translation

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OTHER ART

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39. ASTM E 228-95, "Standard Test Method for Linear Thermal Expansion of Solid Materials With a Vitreous Silica Dilatometer," Annual Book of ASTM Standards, American Society for Testing and Materials, West Conshohocken PA, 1995, pages 1-7.

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Signature:

[Signature]

Date  
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Examiner Initial	Document Number	Issue Date	Name	Classification Class Sub
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<u>h</u>	41. 11-310430	11/1999	JP	+

with attached English abstract and computer translation  
 obtained from the Japanese Patent Office website

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 Signature:

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8/1/03